

Notice of References Cited	Application/Control No. 10/539,355		Applicant(s)/Patent Under Reexamination ALI, DANISH	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,742,533 A	05-1988	Weidner et al.	375/331
*	B	US-4,882,733 A	11-1989	Tanner, Robert M.	714/752
*	C	US-5,105,442 A	04-1992	Wei, Lee-Fang	375/262
*	D	US-5,233,629 A	08-1993	Paik et al.	375/262
*	E	US-5,233,630 A	08-1993	Wolf, Jack K.	375/308
*	F	US-5,396,518 A	03-1995	How, Stephen K.	375/265
*	G	US-5,438,590 A	08-1995	Tzukerman et al.	375/259
*	H	US-5,633,881 A	05-1997	Zehavi et al.	714/756
*	I	US-6,005,897 A	12-1999	McCallister et al.	375/340
*	J	US-6,097,764 A	08-2000	McCallister et al.	375/298
*	K	US-6,236,685 B1	05-2001	Oppedahl, Douglas A.	375/265
*	L	US-2002/0003846 A1	01-2002	Khayrallah et al.	375/341
*	M	US-2002/0004400 A1	01-2002	Fischer et al.	455/456

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
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NON-PATENT DOCUMENTS

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	U	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0067777 A1	06-2002	Jeong, Gibong	375/324
*	B	US-6,434,200 B1	08-2002	Hessel, Clifford	375/265
*	C	US-2002/0122510 A1	09-2002	Yakhnich et al.	375/342
*	D	US-2002/0133781 A1	09-2002	Mikkola et al.	714/790
*	E	US-2002/0131489 A1	09-2002	Allpress et al.	375/233
*	F	US-2002/0150180 A1	10-2002	Malmberg et al.	375/341
*	G	US-6,466,629 B1	10-2002	Isaksson et al.	375/316
*	H	US-2002/0154704 A1	10-2002	Reshef, Ehud	375/262
*	I	US-2002/0159545 A1	10-2002	Ramesh et al.	375/340
*	J	US-2002/0168026 A1	11-2002	Khoini-Poorford, Ramin	375/303
*	K	US-2003/0033574 A1	02-2003	Vasic et al.	714/795
*	L	US-2003/0053535 A1	03-2003	Malkov et al.	375/233
*	M	US-2003/0061003 A1	03-2003	Miyauchi et al.	702/181

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	P					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,529,559 B2	03-2003	Reshef, Ehud	375/262
*	B	US-2003/0109227 A1	06-2003	Chen, Yue	455/75
*	C	US-2003/0115061 A1	06-2003	Chen, Yue	704/240
*	D	US-6,658,071 B1	12-2003	Cheng, Jung-Fu	375/348
*	E	US-6,691,263 B2	02-2004	Vasic et al.	714/709
*	F	US-6,697,441 B1	02-2004	Bottomley et al.	375/340
*	G	US-6,700,926 B1	03-2004	Heikkila et al.	375/221
*	H	US-6,731,700 B1	05-2004	Yakhnich et al.	375/341
*	I	US-6,798,852 B2	09-2004	Khayrallah et al.	375/341
*	J	US-6,823,027 B2	11-2004	Malmberg et al.	375/341
*	K	US-6,944,242 B2	09-2005	Yakhnich et al.	375/341
*	L	US-6,981,202 B2	12-2005	Mikkola et al.	714/790
*	M	US-6,993,070 B1	01-2006	Berthet et al.	375/232

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	P					
	Q					
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NON-PATENT DOCUMENTS

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	U	
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	X	

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,042,938 B2	05-2006	Malkov et al.	375/233
*	B	US-7,106,813 B1	09-2006	Ling, Fuyun	375/343
*	C	US-7,136,435 B2	11-2006	Kolze, Thomas J.	375/341
	D	US-			
	E	US-			
	F	US-			
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	H	US-			
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FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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